


<b>Search Notes</b>  	<b>Application/Control No.</b>  10525668	<b>Applicant(s)/Patent Under Reexamination</b>  HAECKER ET AL.
	<b>Examiner</b>  CHRISTINE T MUI	<b>Art Unit</b>  1797

SEARCHED			
Class	Subclass	Date	Examiner
422	102, 103	12 March 2008	CTM
210	251	03 November 2008	CTM

SEARCH NOTES		
Search Notes	Date	Examiner
See EAST Search Report	12 March 2008	CTM
See Updated EAST Search Report	03 November 2008	CTM

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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